										REV	/ISIC	NS												4
LTR						D	ESC	RIPT	ION							 1	ATE	(YR-I	MO-D	A)	AP	PRO	VED	
LTR						D	ESC	RIPTI	ON								DATE	(YR-1		A)	AF		VED	
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OF SHE		Si	HEET		1	2	3	4	5	6	7	8				Ĺ		<u> </u>	<u>L</u> _	<u> </u>				Щ
		RY	DEFENSE ELECTRONICS SUPPLY CENT DAYTON, OHIO 45444  CHECKED BY  MICROCIRCUITS, DIGITAL, BIPOLAR, A LOW POWER SCHOTTKY TTL, HEX INVERT MONOLITHIC SILICON				AD	VANC	ED															
THIS DRA FOR USE E AND A DEPART	SY ALL I AGENCIE IMENT (	S OF T	MEN HE	TS		DRAWING APPROVAL DAYE 11 MAY 1988 REVISION LEVEL				+	SIZE	SHE	 672			OF		62 8		85	40			

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5962-E757

1. SCOPE			
1.1 Scope. This drawing describes device ith 1.2.1 of MIL-STD-883, "Provisions for ton-JAN devices".	e requirement the use of N	ts for class B mid IL-STD-883 in con	crocircuits in accordance junction with compliant
1.2 Part number. The complete part number	er shall be	as shown in the f	ollowing example:
5962-88540 01 		Case outline (1.2.2)	Lead finish per MIL-M-38510
1.2.1 <u>Device type</u> . The device type shall	l identify	the circuit functi	on as follows:
Device type Generic numb	er	<u>Circuit fu</u>	nction
01 54ALS05A			pen collector outputs
1.2.2 Case outlines. The case outlines as follows:	shall be as	designated in app	endix C of MIL-M-38510, and
Outline letter		se outline	
C D-1 (14-lea 2 C-2 (20-ter	d, .785" x minal, .358	.310" x .200"), du " x .358" x .100")	nal-in-line package , square chip carrier package
1.3 Absolute maximum ratings.			
Supply voltage range Input voltage range		1.2 V dc a 23.1 mW 65°C to +1 +300°C See MIL-M-1	ninimum to +7.0 V dc maximum nt -18 mA to +7.0 V dc 150°C 38510, appendix C
1.4 Recommended operating conditions.			
Supply voltage ( $V_{CC}$ ) Minimum high level input voltage ( $V_{IL}$ ) Maximum low level input voltage ( $V_{IL}$ ) Maximum high level output voltage ( $V_{CC}$ ) Maximum low level output current ( $I_{OL}$ ) Case operating temperature range ( $I_{CC}$ )	)	2.0 V dc 0.7 V dc 5.5 V dc 4.0 mA	to +5.5 V dc 125°C
			-
STANDARDIZED	SIZE		5000 00540
MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER	<u> </u>	REVISION LEVEL	
DAYTON, OHIO 45444	<u> </u>		2

## 2. APPLICABLE DOCUMENTS

2.1 Government specification and standard. Unless otherwise specified, the following specification and standard, of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510

- Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883

Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

- 2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.
  - 3. REQUIREMENTS
- 3.1~ Item requirements. The individual item requirements shall be in accordance with 1.2.1~ of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
  - 3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.
  - 3.2.2 Truth table. The truth table shall be as specified on figure 2.
  - 3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.
- 3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.
- 3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.
- 3.5 <u>Certificate of compliance</u>. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.
- 3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

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	. <del></del> /					1
Test	Symbol	Conditions   -55°C < T <sub>C</sub> < +125°C	Group A   	Limi	its	Unit
Ì	i i	unless otherwise specified	Subgroups	Min '	Max	İ
Low level output voltage	   <b>V</b> OL 	$V_{CC} = 4.5 \text{ V}, V_{IH} = 2 \text{ V}$ $V_{IOL} = 4 \text{ mA}, V_{IL} = 0.7 \text{ V}$	1, 2, 3	l I	0.4	V
Input clamp voltage	I <sub>VIC</sub>	V <sub>CC</sub> = 4.5 V, I <sub>IN</sub> = -18 mA	1, 2, 3		-1.2	V
Low level input current	  I <sub>IL</sub> 	$V_{CC} = 5.5 \text{ V}, V_{IN} = 0.4 \text{ V}$	1, 2, 3		-0.1	   mA 
High level input current	I IIIH1 I	$V_{CC} = 5.5 \text{ V}, V_{IN} = 2.7 \text{ V}$	1, 2, 3	l 	20	   μ <b>A</b>
	I <sub>IH2</sub>	$V_{CC} = 5.5 \text{ V}, V_{IN} = 7.0 \text{ V}$			100	<u> </u>
Supply current, outputs high	Icen	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 0.0 V	1, 2, 3		1.1	mA
Supply current, outputs low	ICCL	V <sub>CC</sub> = 5.5 V, V <sub>IN</sub> = 4.5 V	1, 2, 3	 	4.2	mA
High level output current	I I OH	$V_{CC} = 4.5 \text{ V}, V_{OH} = 5.5 \text{ V}$	1, 2, 3		0.1	   mA 
Functional testing		See 4.3.1c	7, 8	 		   
Propagation delay time, from A to Y	tpLH	V <sub>CC</sub> = 4.5 V to 5.5 V   C <sub>1</sub> = 50 pr *10%	9, 10, 11	23	84	l ns
	  tpHL	$   R_{L}^{L} = 500\Omega \pm 5\% \qquad \underline{1}/$	1	1 4	24	1

Propagation delay limits are based on single output switching. The load circuit shall consist of the specified R<sub>L</sub> and C<sub>L</sub> in series with R<sub>L</sub> tied to  $V_{CC}$  and C<sub>L</sub> tied to GND. The device test point shall be the node between C<sub>L</sub> and R<sub>L</sub>. tpH<sub>L</sub> and tp<sub>LH</sub> voltage waveforms shall be in accordance with method 3003 of MIL-STD-883, with threshold voltage points at 50 percent, tr = tf = 3 ns  $\pm 1$  ns, PRR  $\leq 10$  MHz, and C<sub>L</sub> includes probe and jig capacitance.

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- 3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.
  - 4. QUALITY ASSURANCE PROVISIONS
- 4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
  - a. Burn-in test, method  $1015\ \text{of}\ \text{MIL-STD-883}$ .
    - Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
    - (2)  $T_A = +125$ °C, minimum.
  - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- 4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
  - 4.3.1 Group A inspection.
    - a. Tests shall be as specified in table II herein.
    - b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
    - c. Subgroups 7 and 8 tests shall verify the truth table as specified on figure 2 herein.
  - 4.3.2 Groups C and D inspections.
    - a. End-point electrical parameters shall be as specified in table II herein.
    - b. Steady-state life test conditions, method 1005 of MIL-STD-883:
      - (1) Test condition A or D using the circuit submitted with the certificate of compliance (see  $3.5\ herein$ ).
      - (2)  $T_A = +125$ °C, minimum.
      - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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ase C	Casa 2
<u> </u>	Case 2
1A   1   1   2   2   3   3   3   3   4   4   4   4   4   4	NC   1A   1Y   2A   NC   3A   3Y   GND   NC   4A   5Y   NC   5A   NC   5A   NC   6A   NC   A   NC   A
	4Y 4A 5Y 5A 6Y 6A

FIGURE 1. Terminal connections.

Input A	  Output   Y	
H   L	   L   H	

H = High voltage level, steady state L = Low voltage level, steady state

FIGURE 2. Truth table.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8, 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 9, 10, 11
Groups C and D end-point   electrical parameters   (method 5005)	1, 2, 3

<sup>\*</sup> PDA applies to subgroup 1.

## 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

## 6. NOTES

- 6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

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6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor     CAGE     number	Vendor similar part number <u>1</u> /
5962-8854001CX	01295	SNJ54ALS05AJ
5962-88540012X	01295	SNJ54ALS05AFK

 $\frac{1}{a} / \frac{\text{Caution.}}{\text{acquisition.}} \ \, \text{Do not use this number for item} \\ \frac{\text{acquisition.}}{\text{not satisfy the performance requirements of this}} \\ \text{drawing.}$ 

Vendor CAGE number Vendor name and address

01295

Texas Instruments, Incorporated P.O. Box 6448 Midland, TX 79701

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